Supporting information

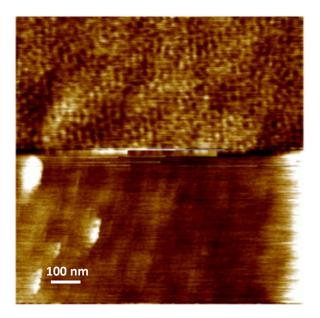


Figure S1. AFM image 0.1 wt% $EGE_{104}EO_{178}$ in water on the silica, with push through the adsorbed layer to the underlying silica substrate shown in the bottom of the image. Imaging force has increased down the image.

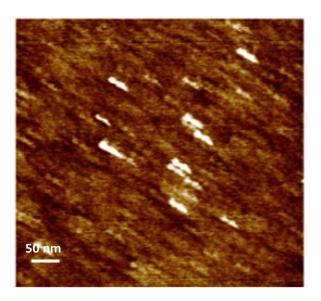


Figure S2. Soft-contact AFM image of the silica-EAN interface.